

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/992,138	FUNCK ET AL.	
Examiner	Art Unit	
Benjamin E. Lanier	2132	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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